

Beamline X20A

Nucleation and Ordering of an Electrodeposited Two-Dimensional Crystal: Real-Time X-ray Scattering and Electronic Measurements

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X-ray Scattering Measurement of Switching Effect in $NbSe_3$

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Observation of Local Tilted Regions in Strain-Relaxed SiGe/Si Buffer Layers Using X-Ray Microdiffraction

P.M. Mooney, J.L. Jordan-Sweet, I.C. Noyan, S.K. Kaldor, and P.-C. Wang (IBM)

Characterization of Substrate/Thin-film Interfaces with X-Ray Microdiffraction

I.C. Noyan, J.L. Jordan-Sweet, E.G. Liniger, and S.K. Kaldor (IBM)

A Cost-effective Method for Minimizing the Sphere-of-confusion Error of X-ray Microdiffractometers

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Scaling in Charge-Density-Wave Relaxation

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Small-Angle X-ray Probes of Phophonate Tubules

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X-ray Diffraction from 10Gb/in² Magentic Thin Film Media

M.F. Toney, J. Li, M. Mirzamaani, X. Bian, M. Doerner, S. Duan, K. Tang, T. Arnoldussen, M. Madison (IBM)

Structural Critical Scattering Study of the Disordered Spin-Peierls System $Cu_{1-x}Mg_xGeO_3$

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